

Applying the Arcface model in the smart attendance problem

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Abstract: In the practical management of learning and work, the demand for automatic attendance systems is increasing to ensure security and efficiency. This topic aims to research and apply the Arcface model to solve the problem of smart attendance. The goal is to build an accurate facial recognition system with high noise resistance, thereby providing a solution for schools, companies, and other organizations. By combining theoretical research on image recognition with experimental deployment of applications on mobile devices, this topic hopes to contribute a useful tool in the field of user management. The system is expected to ensure accuracy, speed, and convenience for attendance.

Keywords: Arcface, face recognition, smart attendance